

Application/Control No.	Applicant(s)/Patent under Reexamination
10/689,060	FUKUDA ET AL.
Examiner	Art Unit
Thinh T. Nguyen	2818

SEARCHED					
Class	Subclass	Date	Examiner		
257	758	1/30/2005	TTN		
257	342	1/30/2005	TTN		
257	341	1/30/2005	TTN		
257	617	1/30/2005	TTN		
257	617	1/31/2005	TTN		
257	329	1/31/2005	TTN		
257	335	1/31/2005	TTN		
257	287	1/31/2005	TTN		

INT	ERFEREN	CE SEARCHED				
Class	Subclass	Date	Examiner			
257	758	1/31/2005	TTN			
257	342	1/31/2005	TTN			
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SEARC (INCLUDING SE	CH NOT	ES STRATEGY)
		DATE	EXMR
EAST		1/30/2005	TTN
EAST		1/31/2005	TTN